

## Absolute Maximum Ratings (Ta=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DSS}$	Drain-Source Voltage	600	V
$I_D$	Drain Current	$T_j = 25^\circ\text{C}$	10
		$T_j = 100^\circ\text{C}$	6.6
$V_{GS(TH)}$	Gate Threshold Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy (note1)	320	mJ
$I_{AR}$	Avalanche Current (note2)	10	A
$P_D$	Power Dissipation ( $T_j = 25^\circ\text{C}$ )	120	W
$T_j$	Junction Temperature(Max)	150	°C
$T_{stg}$	Storage Temperature	-55~+150	°C
$TL$	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

## Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	0.88	°C/W
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	62.5	°C/W

**Electrical Characteristics** (Ta=25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0	600	-	-	V
△BV <sub>DSS</sub> /△T <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> =250μA, Reference to 25°C	-	0.67	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V	-	-	10	μA
		V <sub>DS</sub> =480V, T <sub>J</sub> =125°C			100	
I <sub>GSSF</sub>	Gate-body leakage Current, Forward	V <sub>GS</sub> =+30V, V <sub>DS</sub> =0V	-	-	100	nA
I <sub>GSSR</sub>	Gate-body leakage Current, Reverse	V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V	-	-	-100	

**On Characteristics**

V <sub>GS(TH)</sub>	Date Threshold Voltage	I <sub>D</sub> =250μA, V <sub>DS</sub> =V <sub>GS</sub>	2	-	4	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	I <sub>D</sub> =5.0A, V <sub>GS</sub> =10V	-	0.65	0.72	Ω

**Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0, f=1.0MHz	-	1650	-	pF
C <sub>oss</sub>	Output Capacitance		-	166	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	18	-	

**Switching Characteristics**

T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =300V, I <sub>D</sub> =10A R <sub>G</sub> =25Ω (Note 3,4)	-	23	55	nS
T <sub>r</sub>	Turn-On Rise Time		-	66	150	
T <sub>d(off)</sub>	Turn-Off Delay Time		-	144	300	
T <sub>f</sub>	Turn-Off Rise Time		-	77	165	
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =480V, V <sub>GS</sub> =10V, I <sub>D</sub> =10A (Note 3,4)	-	44	47	nC
Q <sub>gs</sub>	Gate-Source Charge		-	6.7	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	18.5	-	

**Drain-Source Diode Characteristics and Maximum Ratings**

I <sub>s</sub>	Max. Diode Forward Current	-	-	-	10	A
I <sub>SM</sub>	Max. Pulsed Forward Current	-	-	-	40	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>D</sub> =10A	-	-	1.4	V
T <sub>rr</sub>	Reverse Recovery Time	I <sub>s</sub> =10A, V <sub>GS</sub> =0V diF/dt=100A/μs (Note 3)	-	340	-	nS
Q <sub>rr</sub>	Reverse Recovery Charge		-	3.2	-	μC

Notes : 1, L=10mH, IAS=10A, VDD=50V, RG=25 Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

### Typical Characteristics

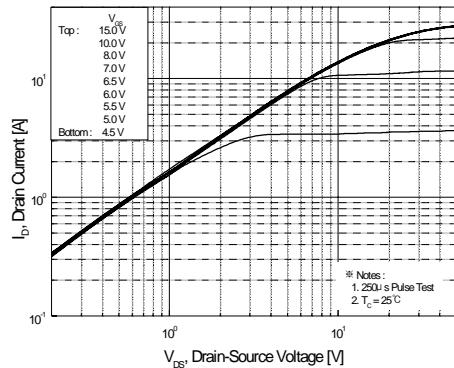


Figure 1. On-Region Characteristics

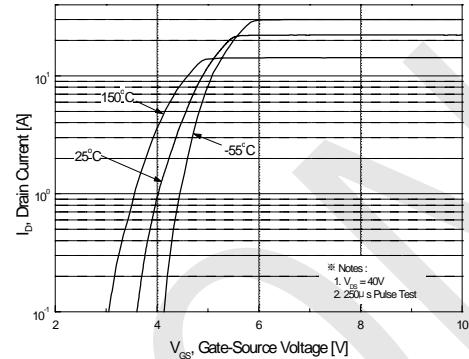


Figure 2. Transfer Characteristics

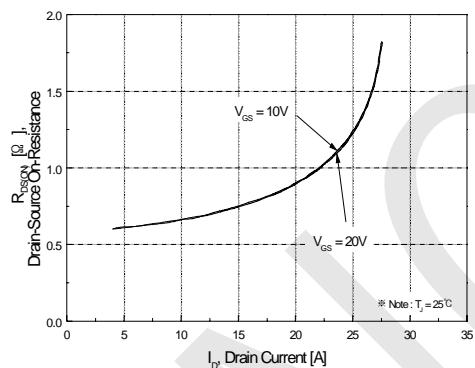


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

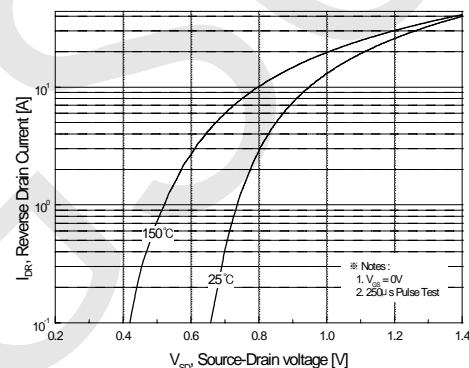


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

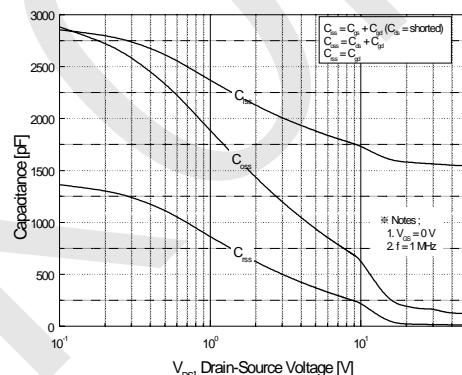


Figure 5. Capacitance Characteristics

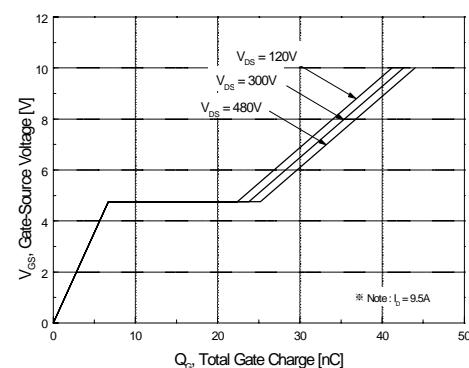
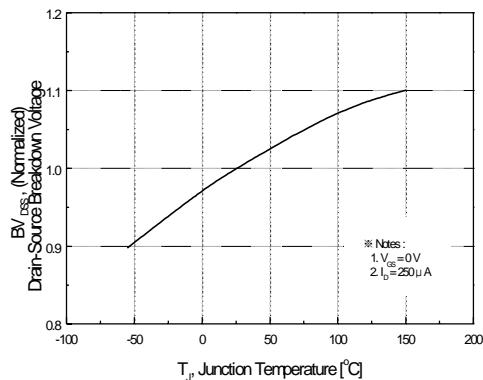
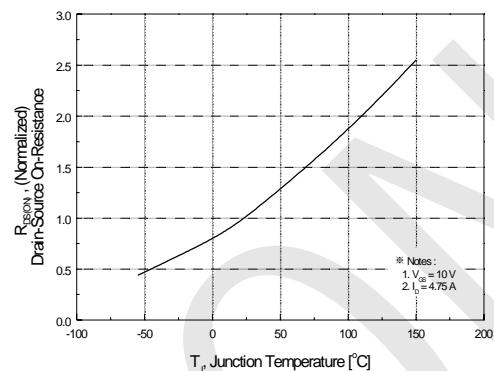


Figure 6. Gate Charge Characteristics

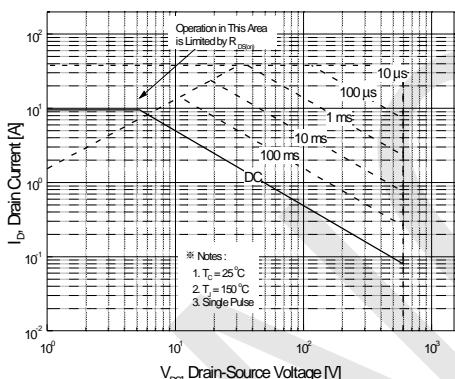
### Typical Characteristics (Continued)



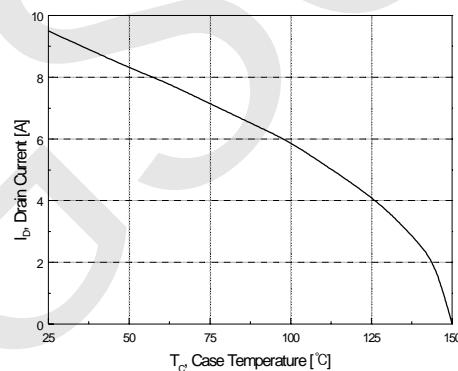
**Figure 7. Breakdown Voltage Variation vs Temperature**



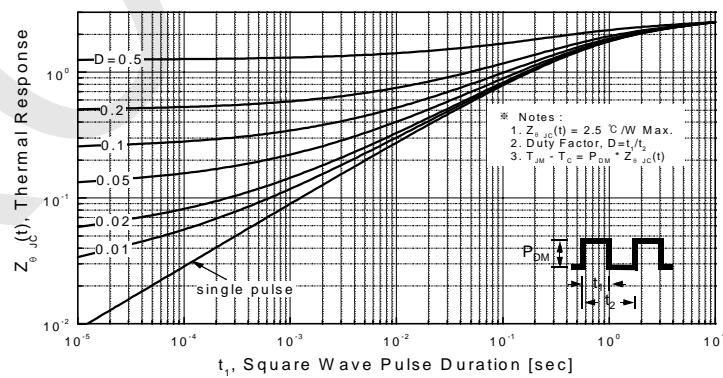
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9-2. Maximum Safe Operating Area**

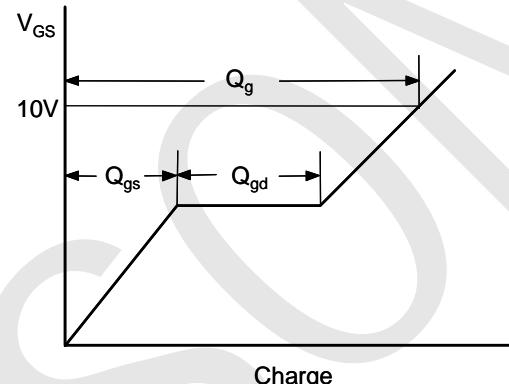
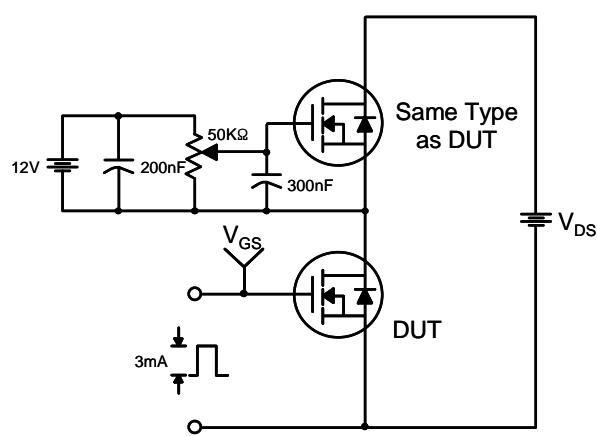


**Figure 10. Maximum Drain Current vs Case Temperature**

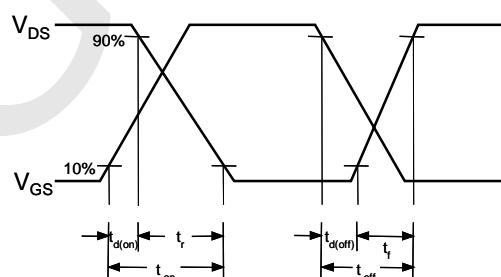
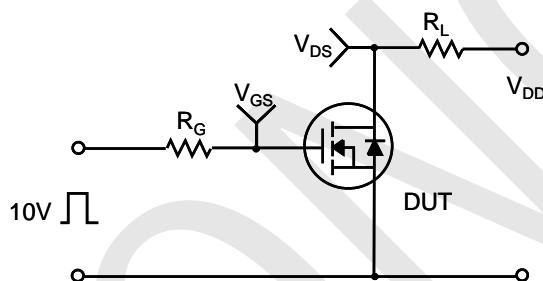


**Figure 11-2. Transient Thermal Response Curve**

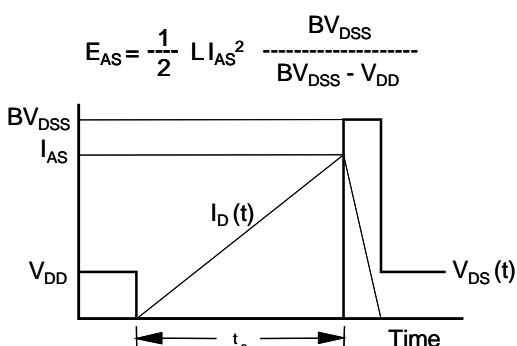
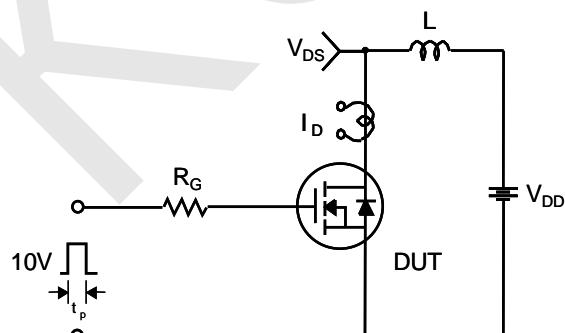
### Gate Charge Test Circuit & Waveform



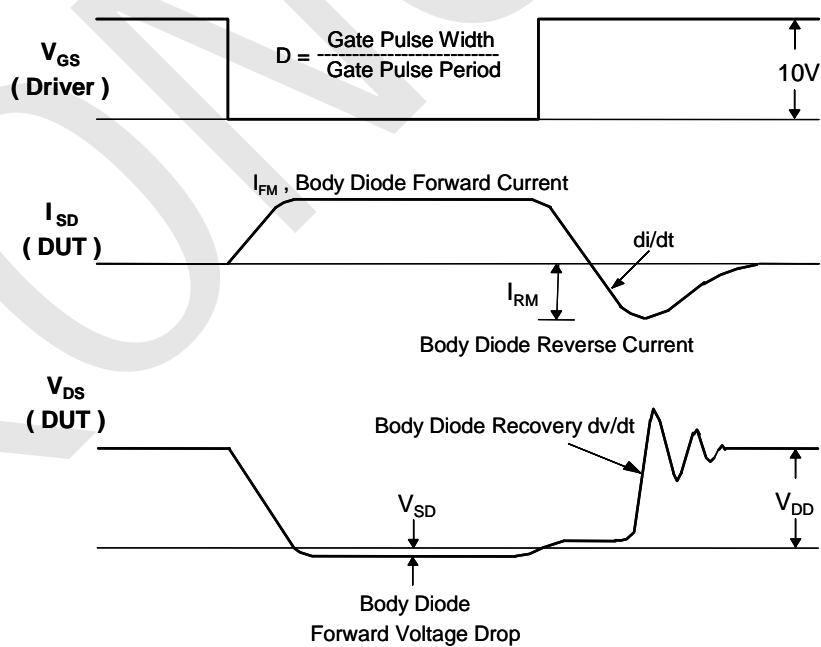
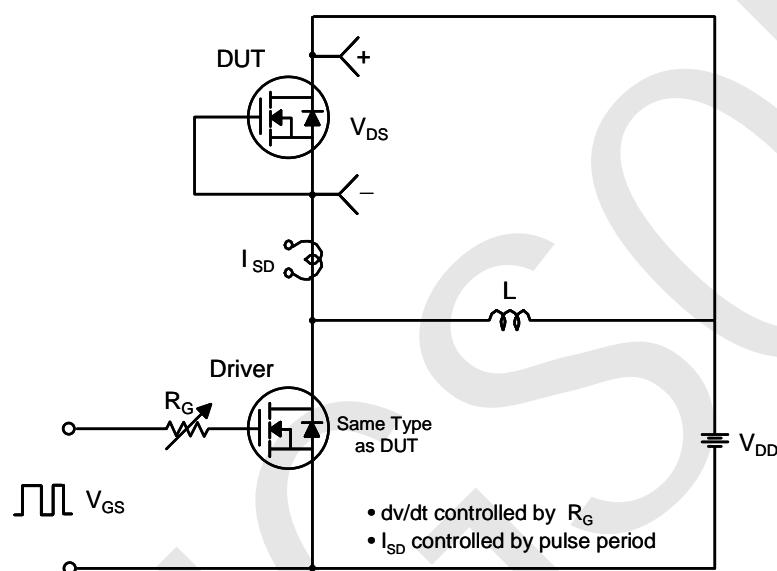
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



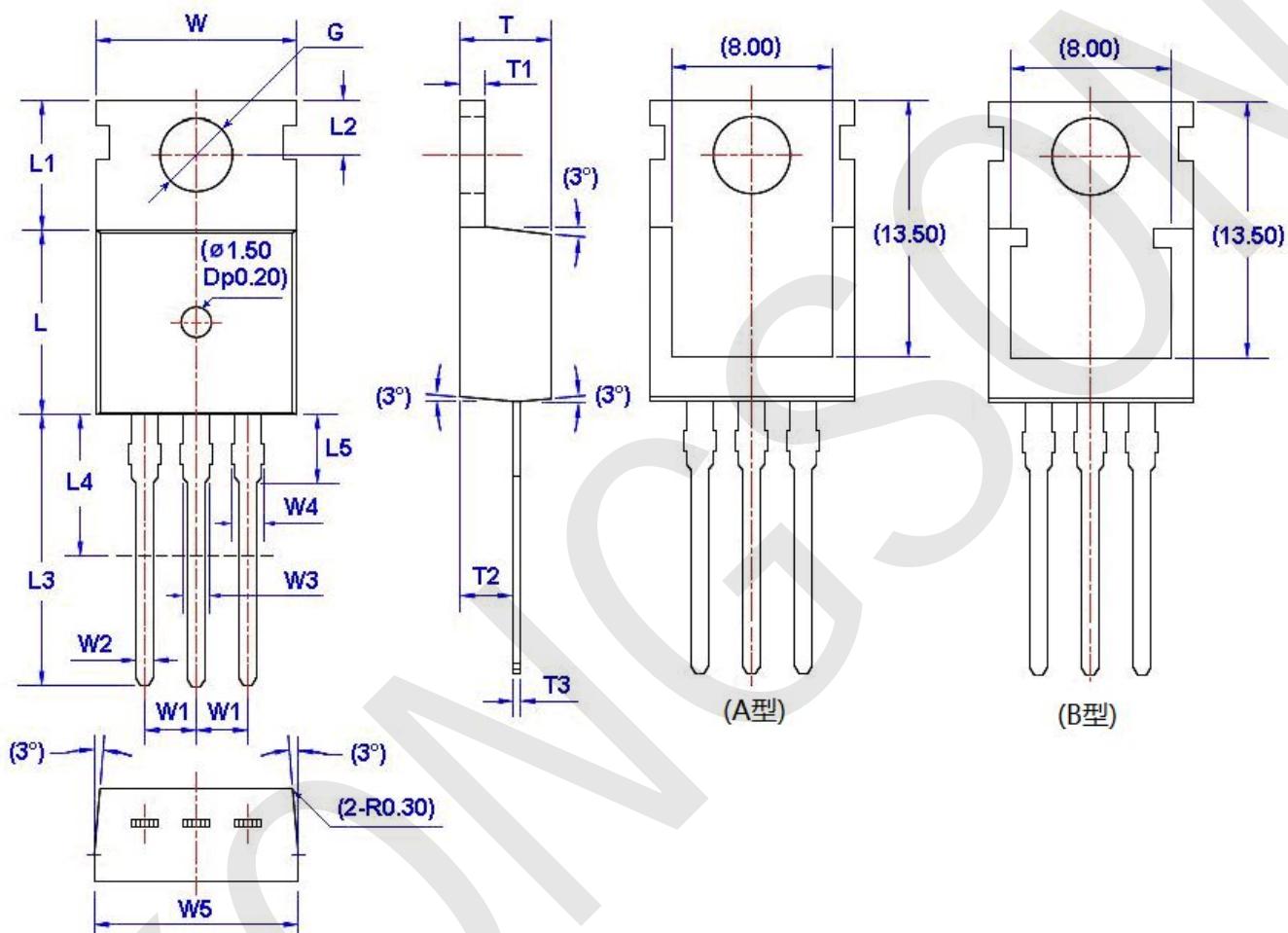
## Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms



Package Dimension

TO-220

Unit:mm



Symbol	Size		Symbol	Size		Symbol	Size		Symbol	Size	
	Min	Max		Min	Max		Min	Max		Min	Max
W	9.66	10.28	W5	9.80	10.20	L4**	6.20	6.60	T3	0.45	0.60
W1	2.54 (TYP)		L	9.00	9.40	L5	2.79	3.30	G(Φ)	3.50	3.70
W2	0.70	0.95	L1	6.40	6.80	T	4.30	4.70			
W3	1.17	1.37	L2	2.70	2.90	T1	1.15	1.40			
W4*	1.32	1.72	L3	12.70	14.27	T2	2.20	2.60			